IDC E	DTOKO NO.	Caballada for	4	44404/77
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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 . of

	Complete if Known	VILE 3
Application Number	10/721,903	E
Filing Date	November 26, 2003	10.000
First Named Inventor	Nobuhiro Komine	MIN S
Art Unit	2851	3.
Examiner Name	D. Rutledge	The manufacture
Attorney Docket Number	3180.0342	911000

	U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS								
Examiner	Cite	Document Number	Issue or	Name of Patentee or	Pages, Columns, Lines, Where				
Initials	No.'	Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Applicant of Cited Document .	Relevant Passages or Relevant Figures Appear				
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Note: Submission of copies of U.S. Patents and published U.S. Patent Applications is not required.

FOREIGN PATENT DOCUMENTS								
Examiner Initials	Cite No.1	Foreign Patent Document  Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>		
D.R.		JP 2001-319871	11/16/01	Nikon Corp.		Abstract		
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Notice of Grounds for Rejection, issued by the Japanese Patent Office, mailed June 21, 2005, in Japanese Patent Application Serial No. P2002-342798, and English-language translation thereof  DIRKSEN et al., "Focus and exposure dose determination using stepper alignment," SPIE (1996), 2726:799-808  STARIKOV, "Exposure Monitor Structure," SPIE (1990), 1261:315-324	Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation
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Examiner Signature	Butte	ether .	Date Considered	11/5/	05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.